

**Search Notes**

Application/Control No.

10/721,512

Examiner

Hai V. Nguyen

Applicant(s)/Patent under  
Reexamination

KOBAYASHI ET AL.

Art Unit

2142

**SEARCHED**

Class	Subclass	Date	Examiner
358	1.14	6/4/2007	HN
358	1.15	6/4/2007	HN
709	201	6/4/2007	HN
709	203	6/4/2007	HN

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST Search (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM; TDB) (see search history printout report)	6/4/2007	HN
Limited classified search: 709/201, 203; 358/1.14, 1.15 (see search history printout report)	6/4/2007	HN